

**Search Notes**

Application/Control No.

09/546,823

Examiner

Andrew Lee

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2616

**SEARCHED**

Class	Subclass	Date	Examiner
370	392, 400	3/1/2006	AL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor and Interference search	3/1/2006	AL